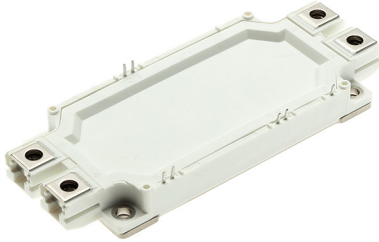


# Half Bridge IGBT Module **multicomp**PRO

**RoHS  
Compliant**



## Features

- Trench Gate, Generation 5, TMOS IGBT
- High Thermal Cycling
- Cu Base with Enhanced Al<sub>2</sub>O<sub>3</sub> Substrates
- 10µs Short Circuit Withstand

## Key Parameters

V <sub>CES</sub>	: 1700 V
V <sub>CE(sat)</sub> * (typ)	: 1.8
I <sub>c</sub> (max)	: 600 A
I <sub>c(RM)</sub> (max)	: 1200 A

\* Measured at the auxiliary terminals

## Applications

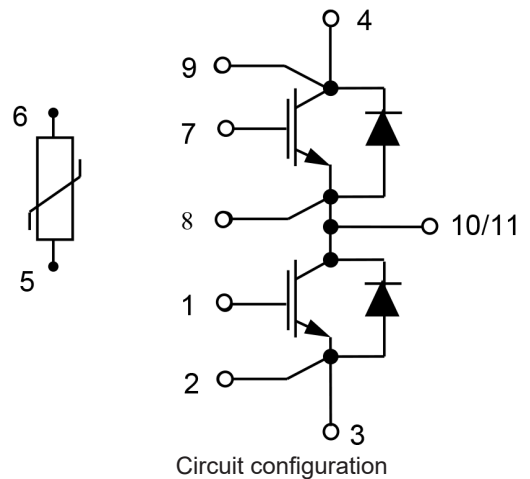
- Wind Turbines
- Power Charging Equipment
- Smart Grid
- High Reliability Inverters

The MP005809 is a half bridge 1700V, trench gate, insulated gate bipolar transistor (IGBT) module with enhanced field stop and implantation technology. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10µs short circuit withstand.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

## Absolute Maximum Ratings

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.



T<sub>case</sub> = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	V <sub>GE</sub> = 0V, T <sub>C</sub> = 25°C	1700	V
V <sub>GES</sub>	Gate-emitter voltage	T <sub>C</sub> = 25°C	±20	
I <sub>c</sub>	Continuous collector current	T <sub>C</sub> = 100°C, T <sub>vj</sub> max = 175°C	600	A
I <sub>c(PK)</sub>	Peak collector current	t <sub>P</sub> = 1ms	1200	
P <sub>max</sub>	Max. transistor power dissipation	T <sub>C</sub> = 25°C, T <sub>vj</sub> = 175°C	3.26	kW
I <sup>2</sup> t	Diode I <sup>2</sup> t value	V <sub>R</sub> = 0, t <sub>p</sub> = 10ms, T <sub>vj</sub> = 150°C	41.5	kA <sup>2</sup> s
V <sub>isol</sub>	Isolation voltage – per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	3400	V

Newark.com/multicomp-pro  
Farnell.com/multicomp-pro  
Element14.com/multicomp-pro

**multicomp**PRO

# Half Bridge IGBT Module **multicomp**PRO

## Thermal and Mechanical Ratings

Internal insulation material	: Al <sub>2</sub> O <sub>3</sub>
Baseplate material	: Cu
Creepage distance – Terminal to heatsink	: 14.5mm
Creepage distance – Terminal to terminal	: 13mm
Clearance – Terminal to heatsink	: 12.5mm
Clearance – Terminal to terminal	: 10mm
CTI (Comparative Tracking Index)	: >200

Symbol	Parameter	Test Conditions	Min.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance– IGBT	Continuous dissipation - junction to case	-	46	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode			80	
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (IGBT)	Mounting torque 5Nm (with mounting grease 1W/m °C)	-	-	
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (Diode)			-	
T <sub>j</sub>	Junction temperature	IGBT	-40	150	°C
		Diode			
F <sub>stg</sub>	Storage temperature range	-		125	
	Screw torque	Mounting – M5	3	6	Nm
		Electrical connections – M6	3	6	

## Electrical Characteristics

T<sub>case</sub> = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Units
I <sub>CES</sub>	Collector cut-off current	V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub>			1	mA
		V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>C</sub> = 125°C			20	
		V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>C</sub> = 150°C			30	
I <sub>GES</sub>	Gate leakage current	V <sub>GE</sub> = ± 20V, V <sub>CE</sub> = 0V			0.5	µA
V <sub>GE(TH)</sub>	Gate threshold voltage	I <sub>C</sub> = 15mA, V <sub>GE</sub> = V <sub>CE</sub>	5.6	6.2	6.4	V
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 600A		1.8	2.25	
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 600A, T <sub>J</sub> = 125°C		2.2	2.6	
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 600A, T <sub>J</sub> = 150°C		2.3	2.7	
I <sub>F</sub>	Diode forward current	DC		600		A
I <sub>FM</sub>	Diode maximum forward current	t <sub>p</sub> = 1ms		1200		
V <sub>F</sub>	Diode forward voltage	I <sub>F</sub> = 600A		1.85	2.2	V
		I <sub>F</sub> = 600A, T <sub>J</sub> = 125°C		2.1	2.3	
		I <sub>F</sub> = 600A, T <sub>J</sub> = 150°C				
C <sub>ies</sub>	Input capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 100kHz		96		nF
Q <sub>g</sub>	Gate charge	±15V		6.1		µC
Q <sub>res</sub>	Reverse transfer capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 100kHz		0.7		nF
L <sub>M</sub>	Module inductance			20		nH
R <sub>INT</sub>	Internal transistor resistance			1		mΩ
SC <sub>Data</sub>	Short circuit current, I <sub>sc</sub>	T <sub>J</sub> = 150°C, V <sub>CC</sub> = 1000V t <sub>p</sub> ≤ 10µs, V <sub>GE</sub> ≤ 15V V <sub>CE(max)</sub> = V <sub>CES</sub> – L* x di/dt IEC 60747-9		2400		A

Newark.com/multicomp-pro  
Farnell.com/multicomp-pro  
Element14.com/multicomp-pro

**multicomp**PRO

# Half Bridge IGBT Module **multicomp** PRO

**Note:**

\* L is the circuit inductance + L<sub>M</sub>

## NTC-Thermistor Data

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Units
R <sub>25</sub>	Rated Resistance	T <sub>C</sub> = 25°C		5		kΩ
ΔR/R	Deviation of R <sub>100</sub>	T <sub>C</sub> = 100°C, R <sub>100</sub> = 493Ω	-5		5	%
P <sub>25</sub>	Power Dissipation	T <sub>C</sub> = 25°C			20	m/W
B <sub>25/50</sub>	B-value	R <sub>2</sub> = R <sub>25</sub> exp [B <sub>25/50</sub> (1/T <sub>2</sub> – 1/(298.15K))]		3375		K
B <sub>25/80</sub>		R <sub>2</sub> = R <sub>25</sub> exp [B <sub>25/80</sub> (1/T <sub>2</sub> – 1/(298.15K))]		3411		
B <sub>25/100</sub>		R <sub>2</sub> = R <sub>25</sub> exp [B <sub>25/100</sub> (1/T <sub>2</sub> – 1/(298.15K))]		3433		

## Electrical Characteristics

T<sub>case</sub> = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 600A V <sub>CE</sub> = 900V V <sub>GE</sub> = ±15V R <sub>G(OFF)</sub> = 1Ω R <sub>G(ON)</sub> = 1Ω L <sub>S</sub> ~ 60nH		dv/dt = 5000V/μs		ns
t <sub>f</sub>	Fall time					
E <sub>OFF</sub>	Turn-off energy loss					
t <sub>d(on)</sub>	Turn-on delay time	I <sub>F</sub> = 600A V <sub>CE</sub> = 900V di/dt = 7700A/μs		di/dt = 7700A/μs		ns
t <sub>r</sub>	Rise time					
E <sub>ON</sub>	Turn-on energy loss					
Q <sub>rr</sub>	Diode reverse recovery charge	I <sub>F</sub> = 600A V <sub>CE</sub> = 900V di/dt = 7700A/μs				μC
I <sub>rr</sub>	Diode reverse recovery current					
E <sub>rec</sub>	Diode reverse recovery energy					

T<sub>case</sub> = 125°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 600A V <sub>CE</sub> = 900V V <sub>GE</sub> = ±15V R <sub>G(OFF)</sub> = 1Ω R <sub>G(ON)</sub> = 1Ω L <sub>S</sub> ~ 60nH		dv/dt = 5000V/μs		ns
t <sub>f</sub>	Fall time					
E <sub>OFF</sub>	Turn-off energy loss					
t <sub>d(on)</sub>	Turn-on delay time	I <sub>F</sub> = 600A V <sub>CE</sub> = 900V di/dt = 7700A/μs		di/dt = 7700A/μs		ns
t <sub>r</sub>	Rise time					
E <sub>ON</sub>	Turn-on energy loss					
Q <sub>rr</sub>	Diode reverse recovery charge	I <sub>F</sub> = 600A V <sub>CE</sub> = 900V di/dt = 7700A/μs				μC
I <sub>rr</sub>	Diode reverse recovery current					
E <sub>rec</sub>	Diode reverse recovery energy					

# Half Bridge IGBT Module **multicomp** PRO

$T_{case} = 150^{\circ}C$  unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Units
$t_{d(off)}$	Turn-off delay time	$I_C = 600A$ $V_{CE} = 900V$ $V_{GE} = \pm 15V$ $R_{G(OFF)} = 1\Omega$ $R_{G(ON)} = 1\Omega$ $L_s \sim 60nH$		870		ns
$t_f$	Fall time				535	
$E_{OFF}$	Turn-off energy loss				194	
$t_{d(on)}$	Turn-on delay time			300		ns
$t_r$	Rise time				86	
$E_{ON}$	Turn-on energy loss				67	
$Q_{rr}$	Diode reverse recovery charge	$I_F = 600A$ $V_{CE} = 900V$ $di/dt = 7700A/\mu s$		270		$\mu C$
$I_{rr}$	Diode reverse recovery current				830	A
$E_{rec}$	Diode reverse recovery energy				209	mJ

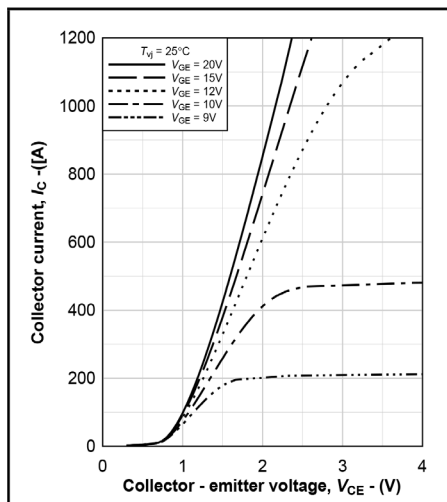


Fig. 3 Typical IGBT output characteristics,  $I_C = f(V_{CE})$

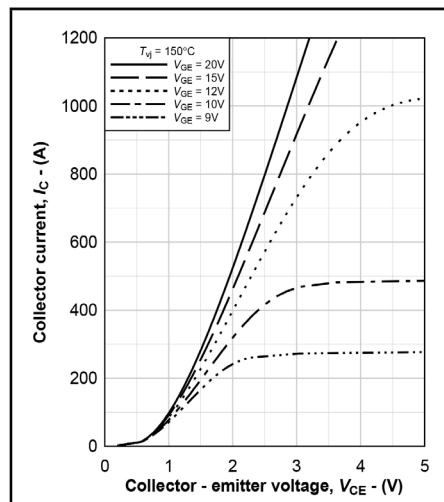


Fig. 4 Typical IGBT output characteristics,  $I_C = f(V_{CE})$

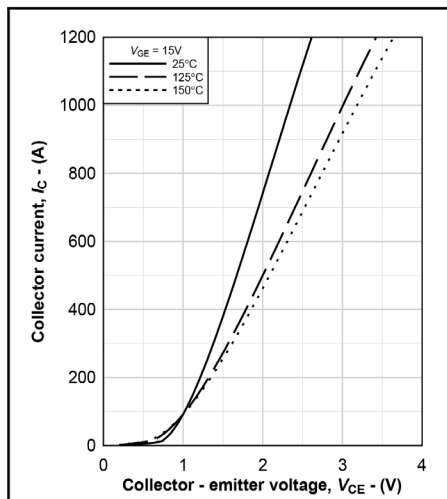


Fig. 5 Typical IGBT output characteristics,  $I_C = f(V_{CE})$

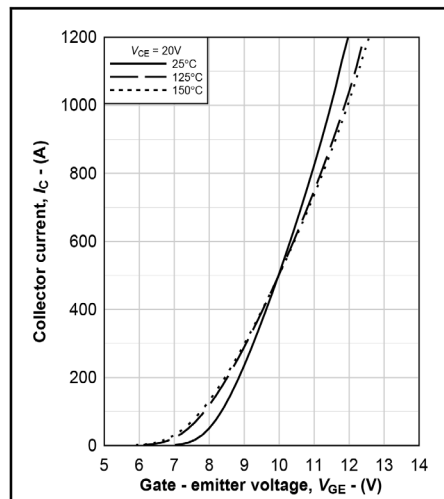


Fig. 6 Typical IGBT transfer characteristics,  $I_C = f(V_{GE})$

# Half Bridge IGBT Module **multicomp**PRO

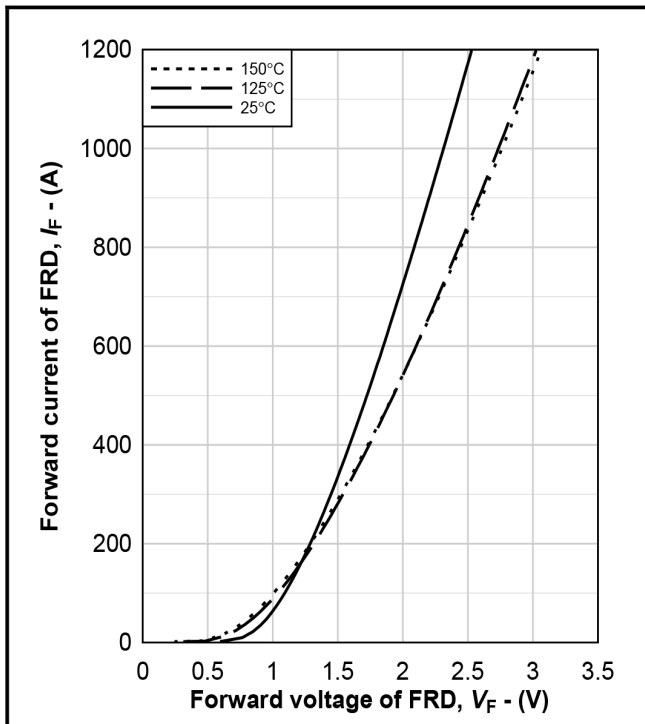


Fig. 7 Typical FRD  $E_{rec}$ ,  $E_{rec} = f(R_G)$

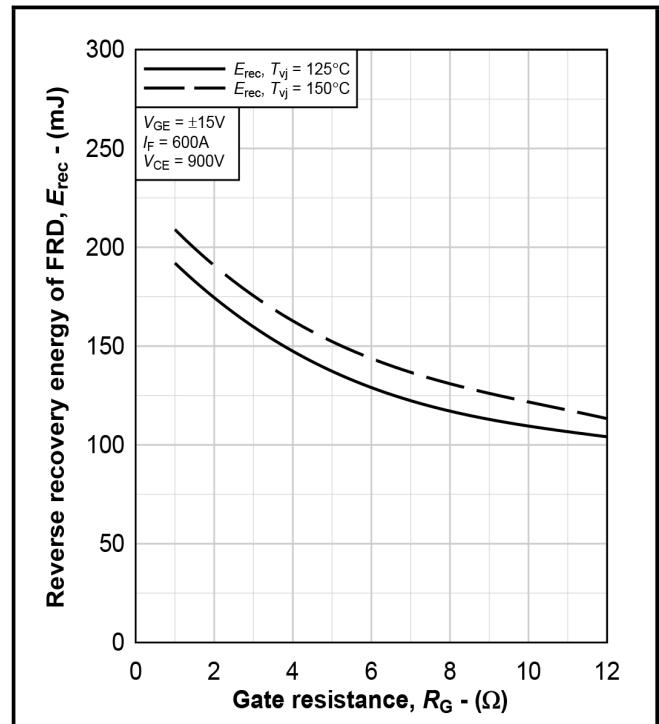


Fig. 8 Typical FRD  $E_{rec}$ ,  $E_{rec} = f(R_G)$

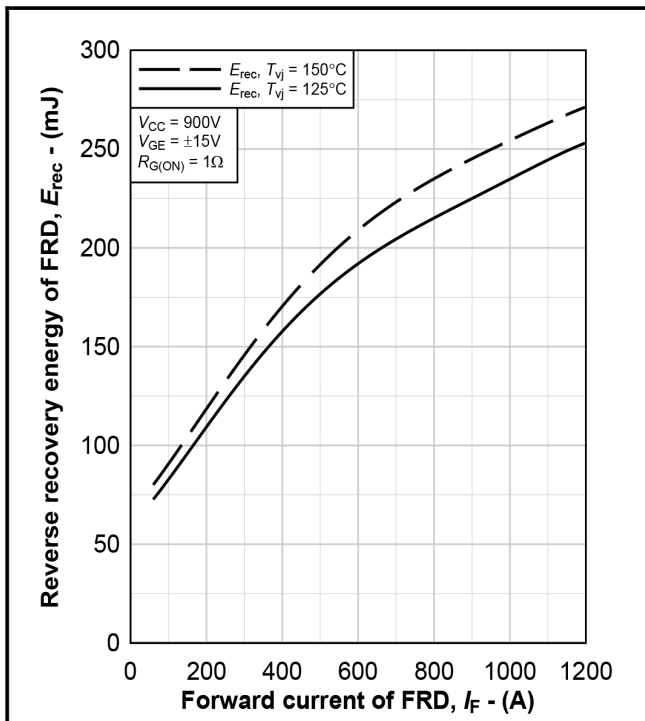


Fig. 9 Typical FRD  $E_{rec}$ ,  $E_{rec} = f(I_F)$

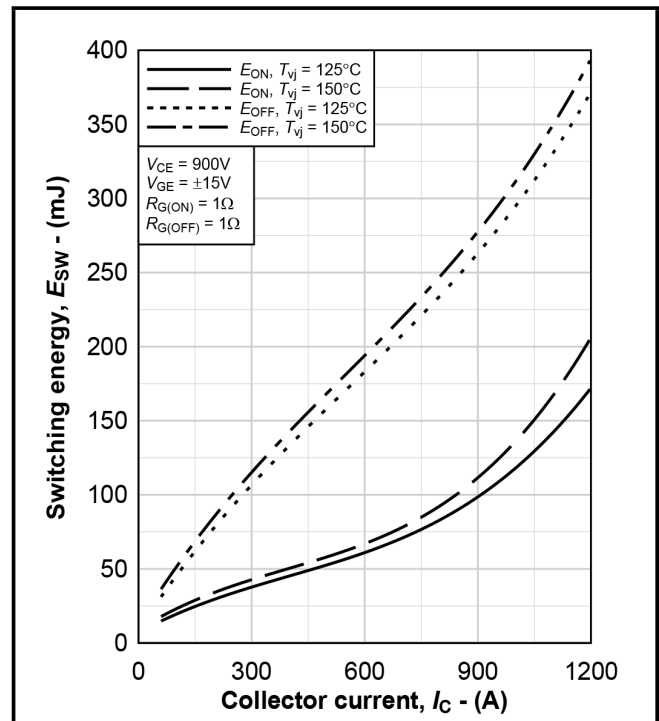


Fig. 10 Typical IGBT switching energy,  $E_{ON} = f(I_C)$ ,  $E_{OFF} = f(I_C)$

# Half Bridge IGBT Module **multicomp**PRO

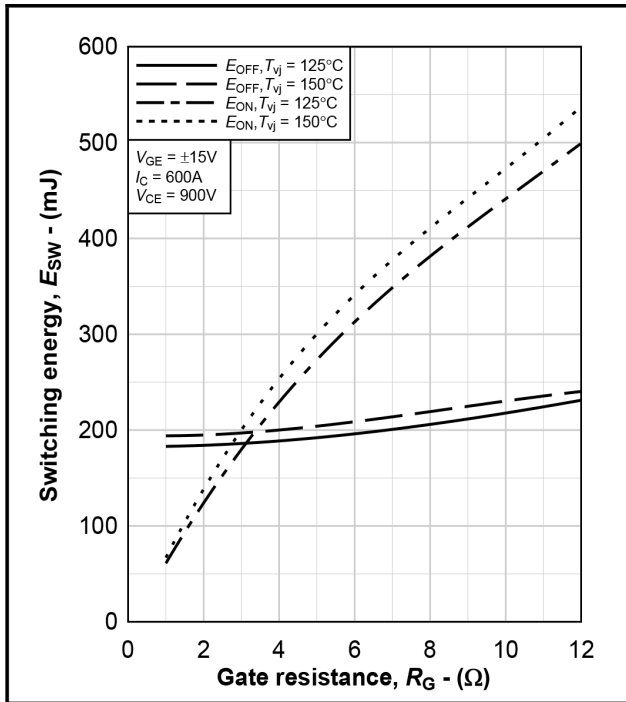


Fig. 11 Typical IGBT switching energy  
 $E_{ON} = f(R_G)$ ,  $E_{OFF} = f(R_G)$

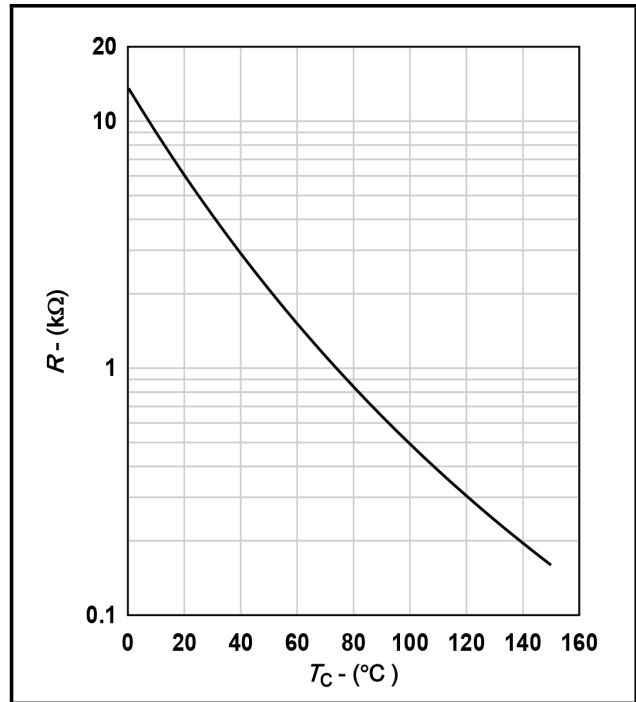


Fig. 12 Typical NTC thermistor characteristic,  $R = f(T_C)$

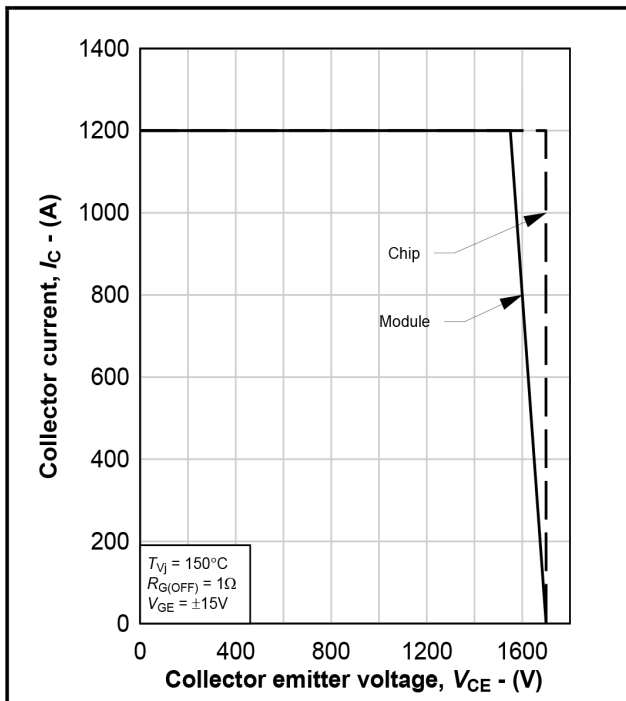


Fig. 13 Reverse bias safe operating area of IGBT,  
 $I_C = f(V_{CE})$

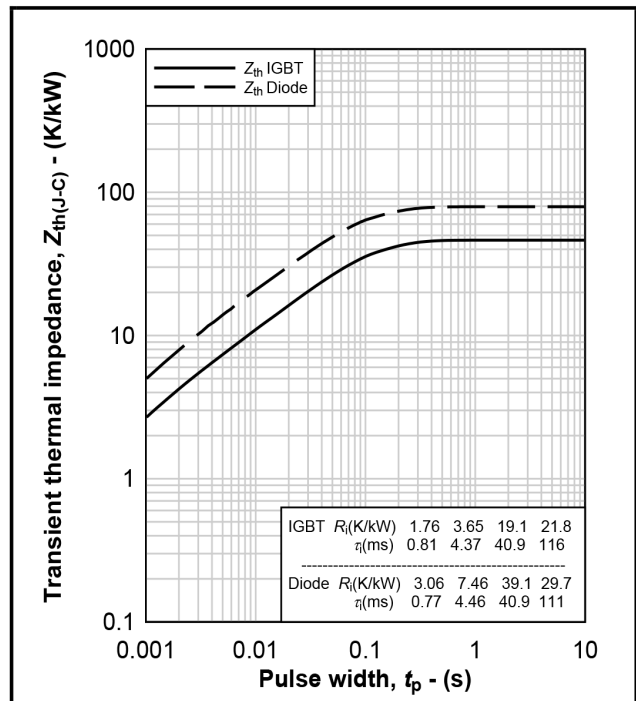


Fig. 14 Transient thermal impedance,  $Z_{th(J-C)} = f(t)$

